

ABSTRACT

APPARATUS AND PROCESS FOR EXAMINING A SURFACE

The apparatus is designed to examine a surface 9 and comprises a polarization analyser element 14, or analyser, placed in the path of a light beam 17 reflected by the said surface 9, a means for taking digital images 13 placed in the path of the beam 17 reflected by the said surface 9 downstream of the analyser 14, and a processing unit 15 capable of calculating the brightness and the intensity of a plurality of pixels of at least one image.

Reference Figure 2.